INF	ORMATION CITATION	ATTY. DOCKET NO. 2336-257		U.S. PATENT APPLICATION NO. 10/811,808				
	APPLICA	ATION OCT.	APPLICANT Seung Wan CHAE et al.					
	(PTO-1	FILING DATE March 30, 2004	GROUP 2814					
		U.S.	PATENT DO	CUMENTS				
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME		CLASS	SUBCLASS	FILI DA	
								
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EXAMINER'S		FOREIC	ON PATENT	DOCUMENTS				
INITIALS	PATENT NO.	DATE	COUNTRY		CLASS	SUBCLASS	Yes	No No
WS	10-173224	6/1998	Japan				Х	
	09-129919	5/1997		Japan			Х	
	10-173222	6/1998		Japan			Х	
	2001-035796	2/2001		Japan			Х	
	09-129933	5/1997		Japan			Х	
	10-341039	12/1998		Japan			х	
W	08-032115	2/1996		Japan			х	
	OTHER	R ART (Includin	g Author, Ti	lle, Date, Pertinent	Pages, Et	:.)		
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not considered. Include copy of this form with next communication to Applicant.

INF	ORMATION	ATTY. DOCKET NO. 2336-257		U.S. APPLICATION NO. Not yet assigned					
CITATION IN AN APPLICATION				APPLICANT Seung Wan CHAE et al.					
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WSL	5,563,422	10/1996	Nakamura et al.						
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EXAMINER'S INITIALS	PATENT NO.	DATE	C	COUNTRY	CLASS	SUBCLASS	Trens Yes	No No	
							 		
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